Research on the Reliability of Sealant Materials for Narrow Border Products

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With the development of technology, narrow border products have become one of the research hotspots in the field of LCD. These products put forward higher requirement for sealant materials, especially the material reliability. Sealant pollution is the focus of the reliability assessment. In this paper, a new test method was used to study the pollution of seal materials in the design of simulated narrow border products, also the mechanism of sealant pollution was explored, we hope that our research could provide direction for the development and revision of sealant materials for narrow border products.